



Accredited by the Swiss Federal Office of Metrology and Accreditation
 The Swiss Accreditation Service is one of the signatories to the EA
 Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Client **CCS (Auden)**

Certificate No: **EX3-3554_Nov04**

CALIBRATION CERTIFICATE

Object **EX3DV4 - SN:3554**

Calibration procedure(s) **QA CAL-01.v5**
Calibration procedure for dosimetric E-field probes

Calibration date: **November 19, 2004**

Condition of the calibrated item **In Tolerance**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
 The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^{\circ}\text{C}$ and humidity $< 70\%$.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	5-May-04 (METAS, No. 251-00388)	May-05
Power sensor E4412A	MY41495277	5-May-04 (METAS, No. 251-00388)	May-05
Reference 3 dB Attenuator	SN: S5054 (3c)	10-Aug-04 (METAS, No. 251-00403)	Aug-05
Reference 20 dB Attenuator	SN: S5086 (20b)	3-May-04 (METAS, No. 251-00389)	May-05
Reference 30 dB Attenuator	SN: S5129 (30b)	10-Aug-04 (METAS, No. 251-00404)	Aug-05
Reference Probe ES3DV2	SN: 3013	8-Jan-04 (SPEAG, No. ES3-3013_Jan04)	Jan-05
DAE4	SN: 617	26-May-04 (SPEAG, No. DAE4-617_May04)	May-05
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Power sensor HP 8481A	MY41092180	18-Sep-02 (SPEAG, in house check Oct-03)	In house check: Oct 05
RF generator HP 8648C	US3642U01700	4-Aug-99 (SPEAG, in house check Dec-03)	In house check: Dec-05
Network Analyzer HP 8753E	US37390585	18-Oct-01 (SPEAG, in house check Nov-03)	In house check: Nov 04

	Name	Function	Signature
Calibrated by:	Nico Vetterli	Laboratory Technician	
Approved by:	Katja Pokovic	Technical Manager	

Issued: December 7, 2004

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.



Accredited by the Swiss Federal Office of Metrology and Accreditation
 The Swiss Accreditation Service is one of the signatories to the EA
 Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
Polarization ϕ	ϕ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- CENELEC EN 50361, "Basic standard for the measurement of Specific Absorption Rate related to human exposure to electromagnetic fields from mobile phones (300 MHz - 3 GHz), July 2001

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E²-field uncertainty inside TSL (see below *ConvF*).
- NORM(f)_{x,y,z}** = NORM_{x,y,z} * frequency_response (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * *ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DASY 4.3 B17 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

Probe EX3DV4

SN:3554

Manufactured:	July 13, 2004
Calibrated:	November 19, 2004

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

DASY - Parameters of Probe: EX3DV4 SN:3554

Sensitivity in Free Space^A

Diode Compression^B

NormX	0.39 ± 9.9%	$\mu\text{V}/(\text{V}/\text{m})^2$	DCP X	92 mV
NormY	0.41 ± 9.9%	$\mu\text{V}/(\text{V}/\text{m})^2$	DCP Y	92 mV
NormZ	0.42 ± 9.9%	$\mu\text{V}/(\text{V}/\text{m})^2$	DCP Z	92 mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL **900 MHz** **Typical SAR gradient: 5 % per mm**

Sensor Center to Phantom Surface Distance		2.0 mm	3.0 mm
SAR _{be} [%]	Without Correction Algorithm	3.7	1.1
SAR _{be} [%]	With Correction Algorithm	0.2	0.4

TSL **1750 MHz** **Typical SAR gradient: 10 % per mm**

Sensor Center to Phantom Surface Distance		2.0 mm	3.0 mm
SAR _{be} [%]	Without Correction Algorithm	4.8	2.4
SAR _{be} [%]	With Correction Algorithm	0.8	0.8

Sensor Offset

Probe Tip to Sensor Center **1.0 mm**

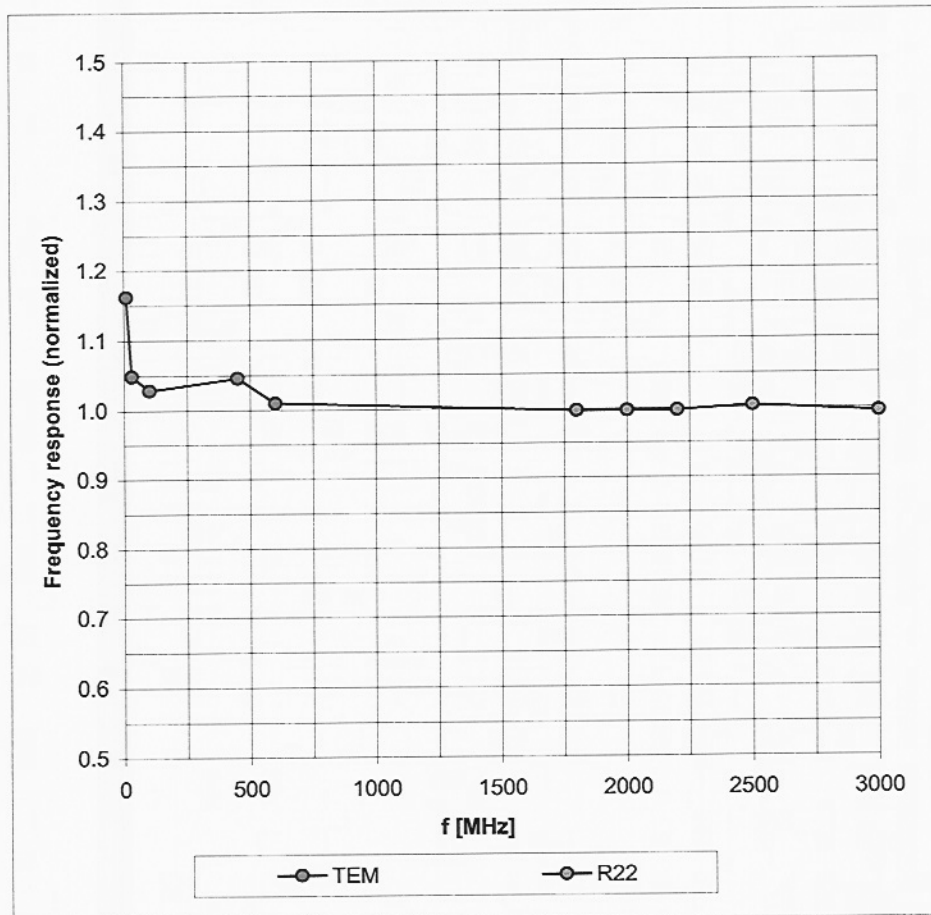
The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor $k=2$, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E^2 -field uncertainty inside TSL (see Page 8).

^B Numerical linearization parameter: uncertainty not required.

Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)